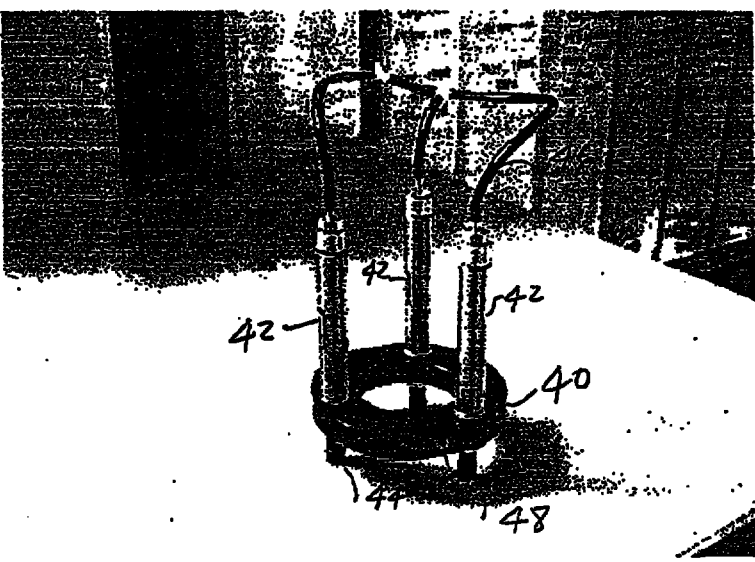


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INTERNATIONAL APPLICATION PUBLISHED UNDER THE PATENT COOPERATION TREATY (PCT)

(51) International Patent Classification 7 : H01L	A2	(11) International Publication Number: WO 00/48232 (43) International Publication Date: 17 August 2000 (17.08.00)
(21) International Application Number: PCT/US00/01489 (22) International Filing Date: 20 January 2000 (20.01.00) (30) Priority Data: 09/248,783 12 February 1999 (12.02.99) US 09/449,023 24 November 1999 (24.11.99) US (71) Applicant: HYPERVISION, INC. [US/US]; 46560 Fremont Boulevard #414, Fremont, CA 94538 (US). (72) Inventors: KUJAWA, Thomas, Joseph; 34379 Livorna Terrace, Fremont, CA 94555 (US). CHIANG, Ching-Lang; 18358 Mill Street, Saratoga, CA 95070 (US). KHURANA, Neeraj; 15071 Becky Lane, Monte Sereno, CA 95030 (US). SABBINENI, Prasad; 43555 Grimmer Blvd., Apt. H270, Fremont, CA 94538 (US). HURLEY, Daniel, T.; 2758 Derby Drive, San Ramon, CA 94583 (US). (74) Agents: WOODWARD, Henry, K. et al.; Townsend and Townsend and Crew LLP, Two Embarcadero Center, 8th Floor, San Francisco, CA 94111-3834 (US).		(81) Designated States: AE, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BY, CA, CH, CN, CR, CU, CZ, DE, DK, DM, EE, ES, FI, GB, GD, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW, MX, NO, NZ, PL, PT, RO, RU, SD, SE, SG, SI, SK, SL, TJ, TM, TR, TT, TZ, UA, UG, UZ, VN, YU, ZA, ZW, ARIPO patent (GH, GM, KE, LS, MW, SD, SL, SZ, TZ, UG, ZW), Eurasian patent (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM), European patent (AT, BE, CH, CY, DE, DK, ES, FI, FR, GB, GR, IE, IT, LU, MC, NL, PT, SE), OAPI patent (BF, BJ, CF, CG, CI, CM, GA, GN, GW, ML, MR, NE, SN, TD, TG). Published <i>Without international search report and to be republished upon receipt of that report.</i>
(54) Title: DYNAMIC STRUCTURAL COUPLING MECHANISM FOR REDUCING OPTICAL DEGRADATION IN VIBRATING ENVIRONMENTS 		
(57) Abstract Vibration damping apparatus for vibrating environment such as a light emission microscope and an integrated circuit test head includes a rigid member with remotely controlled clamping means attached to spaced portions of the member. The clamping means engage the microscope and the test head for reducing vibrations, and the clamping means can be readily deactivated for moving the microscope or the test head for alignment purposes. Advantageously, two or more rigid members including pneumatic cylinders can be positioned around the device under test while permitting the use of mechanical probes for engaging nodes of an integrated circuit for test purposes.		